

IN THE CLAIMS:

Please amend claims 14–21 and 22-23.

Claims 1 – 13 (Canceled)

14. (Currently amended) Method for measuring the geometry and surface evenness of one side of a moving metal strip comprising:

providing a moving metal strip having a surface to be measured;

providing a light source and a transparency between said light source and said metal strip surface;

by producing a pattern on ~~that one side of~~ the metal strip surface to be measured using a said light source, wherein said light source can produce a changeable pattern on the metal surface ~~by means of projection with the aid of a said transparency, and a camera,~~
~~wherein a pattern usable for the measuring situation is selected and produced~~
viewing the pattern on said metal strip surface with a camera; and
determining the geometry and surface evenness of said metal strip surface.

15. (Currently Amended) Method according to claim 14, ~~characterized in that the~~
comprising producing said pattern is produced with the aid of a liquid-crystal device.

16. (Currently Amended) Method according to claim 14, ~~characterized in~~ comprising
filtering elastic form changes using the initially detected peaks and separating the peaks according to different frequencies and wavelength on account of strip movements.

17. (Currently Amended) Method according to claim 14, ~~characterized by~~ comprising
measuring determining said geometry by using the edge boundary of the strip.

18. (Currently Amended) Method according to claim 17, ~~characterized in that~~ wherein the strip width or cut length is determined from the edge boundary.

19. (Currently Amended) Method according to claim 14, ~~characterized in~~ further comprising measuring the geometry of a known element of a measuring device and generating by computation a reference plane and a reference phase image from said measured geometry.

20. (Currently Amended) Method for measuring the geometry and surface evenness of one side of a moving metal strip by comprising:

providing a moving metal strip having a surface to be measured;

providing a light source disposed above said moving metal strip and

emitting light from said light source;

delivering said light through a transparency onto said metal surface;

producing a pattern on the metal surface to be measured using a light source, ~~and a camera~~, wherein the pattern on ~~that~~ said one side of the metal surface to be measured is produced by means of projection with the aid of said transparency; ~~characterized in~~

filtering elastic form changes using the initially detected peaks and separating the peaks according to different frequencies and wavelength on account of strip movements[.]; and

viewing the pattern formed on said metal surface evenness with a camera.

21. (Currently amended) Method for measuring the geometry and surface evenness of one side of a moving metal strip by comprising:

providing a moving metal strip having a surface to be measured;

providing a light source disposed above said moving metal strip and

emitting light from said light source;

delivering said light through a transparency onto said metal surface;

producing a pattern on that one side of the metal strip to be measured

using a light source, ~~and a camera~~, wherein the pattern on the metal surface to be measured is produced by means of projection with the aid of

said transparency; ;

viewing said formed pattern with a camera; ~~characterized by measuring~~
and

determining said strip geometry and surface evenness by using the edge
boundary of the said strip.

22. (Previously presented) Method according to claim 21, characterized in that the strip width or cut length is determined from the edge boundary.

23. (Currently amended) Method for measuring the geometry and surface evenness of one side of a moving metal strip by comprising:

providing a moving metal strip having a surface to be measured;

providing a light source disposed above said moving metal strip and

emitting light from said light source;

delivering said light through a transparency only said metal surface;

producing a pattern on that one side of the metal surface to be measured using a light source, ~~and a camera~~, wherein the pattern on the metal surface to be measured is produced by means of projection with the aid of said transparency, characterized in viewing said formed pattern with a camera measuring the geometry of a known element of a measuring device and generating by computation a reference plane and a reference phase image from said measured geometry[.]; and comparing said pattern produced on said strip to said reference phase image.

24. (Previously Presented) Method according to claim 14, characterized in that a line pattern is produced on the metal surface.

25. (Previously Presented) Method according to claim 20, characterized in that a line pattern is produced on the metal surface.

26. (Previously Presented) Method according to claim 21, characterized in that a line pattern is produced on the metal surface.

27. (Previously Presented) Method according to claim 23, characterized in that a line pattern is produced on the metal surface.